

Powder Diffraction

W. Wong-Ng	The ICDD/PDF Coverage of the High T_c Superconductor and Related Compounds in the A-R-Cu-O Systems (A = Ba, Sr and Ca, and R = Lanthanides and Y)	125
A.N. Sapozhnikov, E.K. Vasil'ev and P. Bayliss	On Indexing X-Ray Diffraction Powder Patterns of Cubic Lazurites with an Incommensurate-Modulated Structure	134
J. Dyakonov <i>et al.</i>	Interlaboratory Tests of X-Ray Quantitative Phase Analysis	137
B.J. Reardon and C.R. Hubbard	A Review of the XRD Data of the Phases Present in the CaO-SrO-CuO System	142
D. Dragoi	A Geometric Factor for Asymmetric Diffraction	149
J.C. Taylor and Z. Rui	Simultaneous Use of Observed and Calculated Standard Profiles in Quantitative XRD Analysis of Minerals by the Multiphase Rietveld Method: The Determination of Pseudorutile in Mineral Sands Products	152
D.C. Azubike, A. Chrysanthou and U.O. Igiehon	A Crystallographic Re-Examination of the $(Fe,W)_6C$ Phase Field in the Fe-W-C-System	162
S.E. Rasmussen	The Use of a Post Diffraction Germanium Monochromator with a Bragg-Brentano Type Powder Diffractometer	164
J.M. Amigó <i>et al.</i>	Crystal Data for Complexes of Co(II) and Ni(II) Perchlorates with Mepirizole	166
A. Meden and M. Čeh	Powder Data for $Ba_3Ca_2Ti_2O_9$	169
G. Bandoli, M. Nicolini and A. Ongaro	Powder Diffraction Data of Three Tetrahydropyridinyl Oxime Cognition Activators of Formula $C_8H_{15}N_2O^+Cl^-$	170
D.J. Kim and C.R. Hubbard	X-Ray Powder Diffraction Data for Tetragonal Zirconia Solid Solutions in System ZrO_2 - $YTaO_4$	174
X. Jing, C. Zheng and A.R. West	Barium Rare Earth Titanates: X-Ray Characterization of $BaR_2Ti_3O_{10}$ and $BaR_2Ti_4O_{12}$: R = Lanthanide	176
Lj. Karanović and D. Poleti	A FORTRAN Program for Conversion of PC-APD Data Files into ASCII Files	179
	International Report	180
	Calendar of Meetings	180
	Correspondents Reports	181
	Book Review	182
	Short Courses and Workshops	183
	Computer Comments	184



Volume 7 Number 3 September 1992

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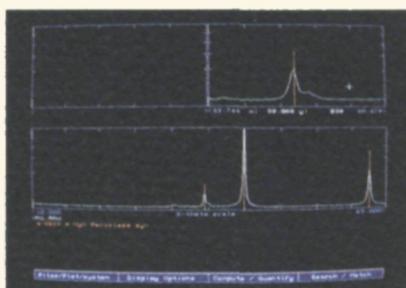
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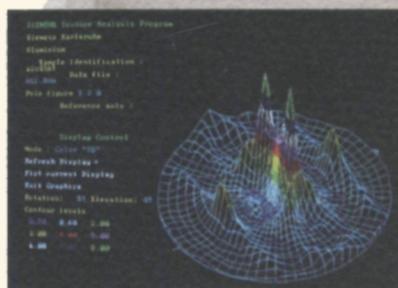
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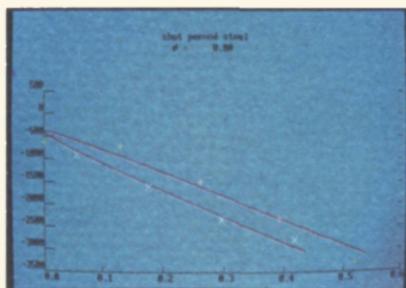
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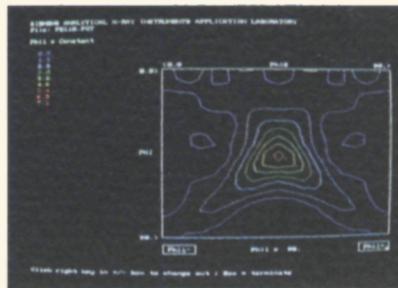
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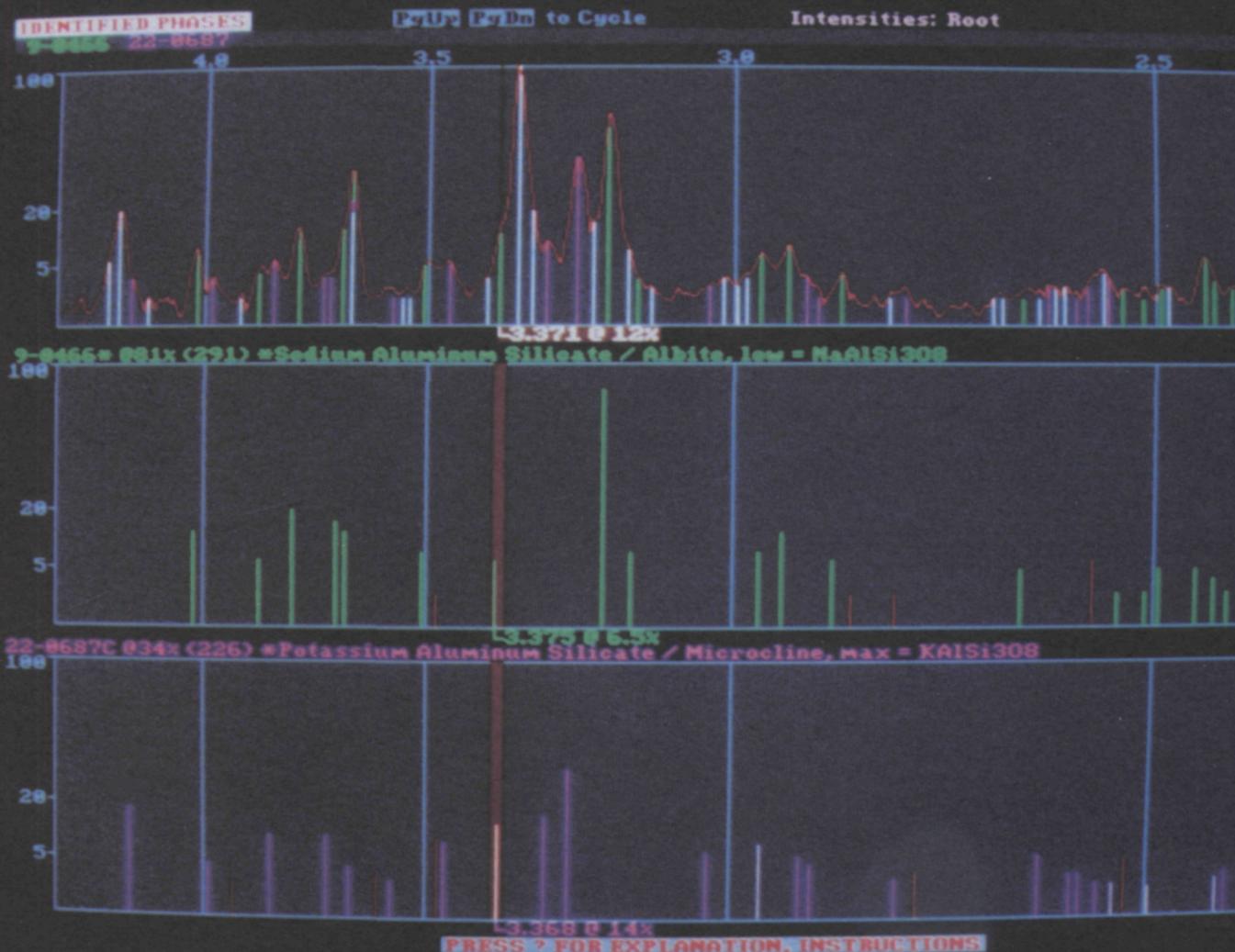
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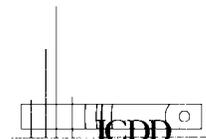
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Postal Information. Powder Diffraction (ISSN 0885-7156) is published quarterly for \$55.00 a year (U.S. and Canada) by JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, Pennsylvania 19081. JCPDS principal office: 1601 Park Lane, Swarthmore, Pa. 19081. Julian Messick, Jr., General Manager. © 1990 JCPDS-International Centre for Diffraction Data. Postmaster: Send address changes to JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, Pennsylvania 19081.

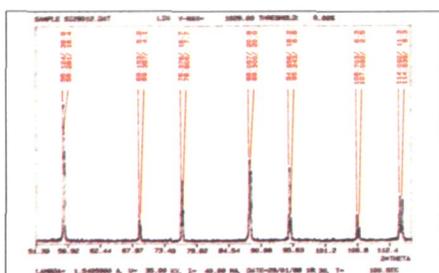
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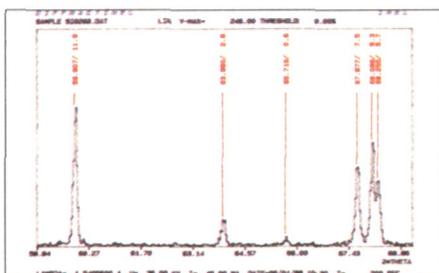
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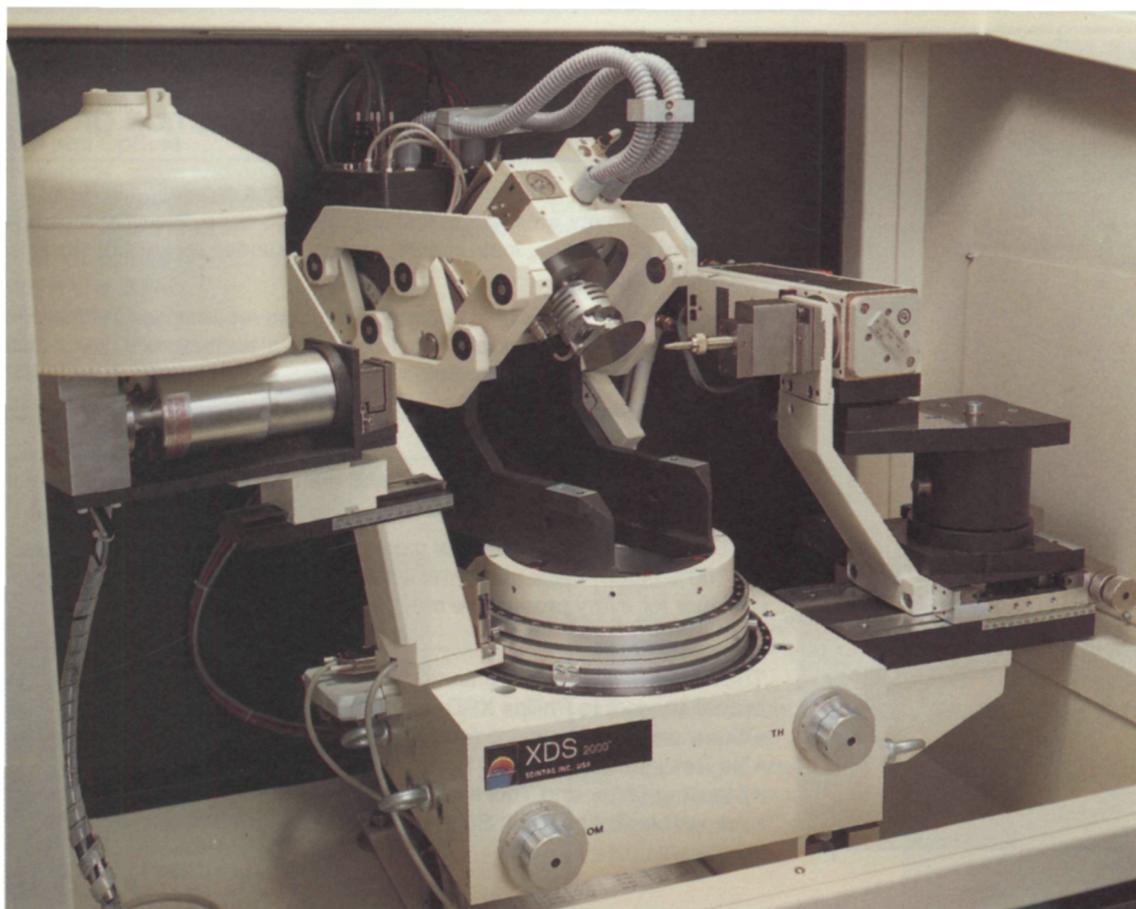
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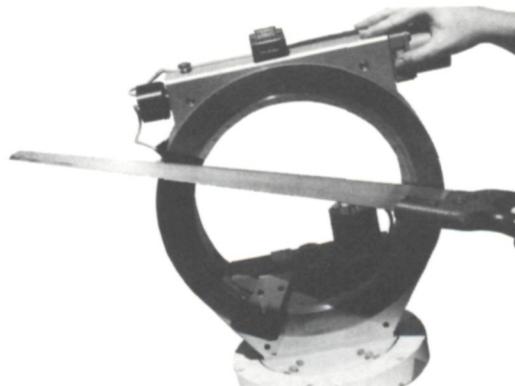
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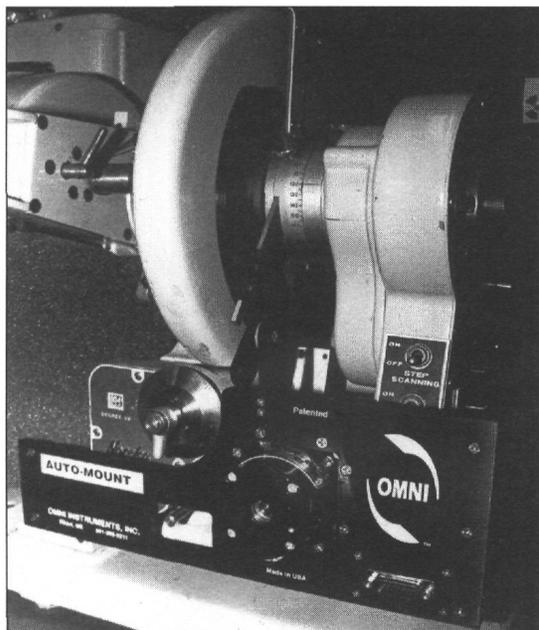


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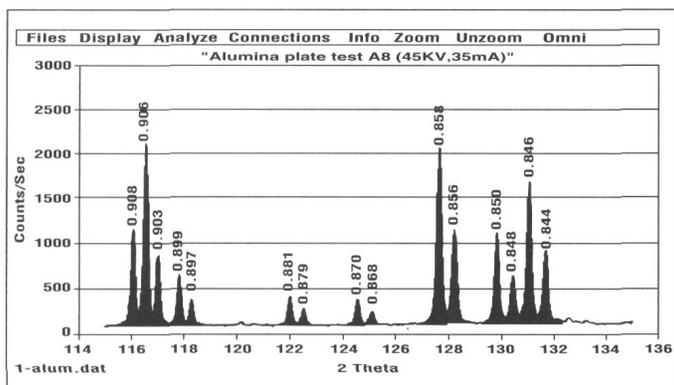
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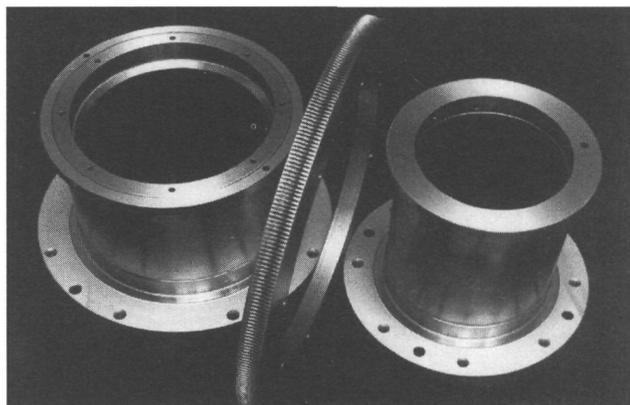


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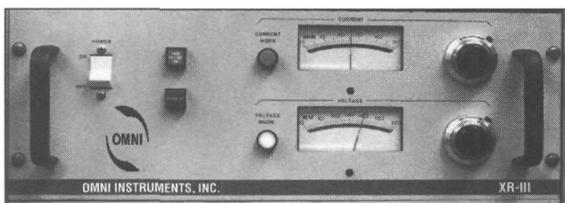
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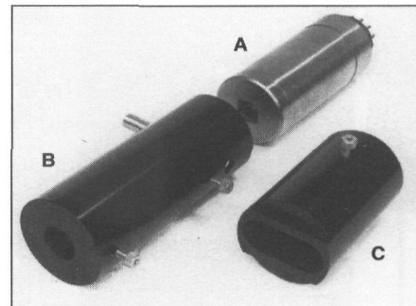
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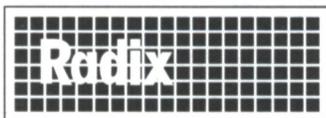
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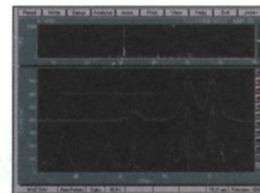
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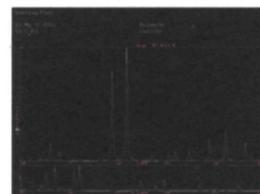
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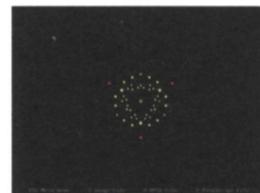
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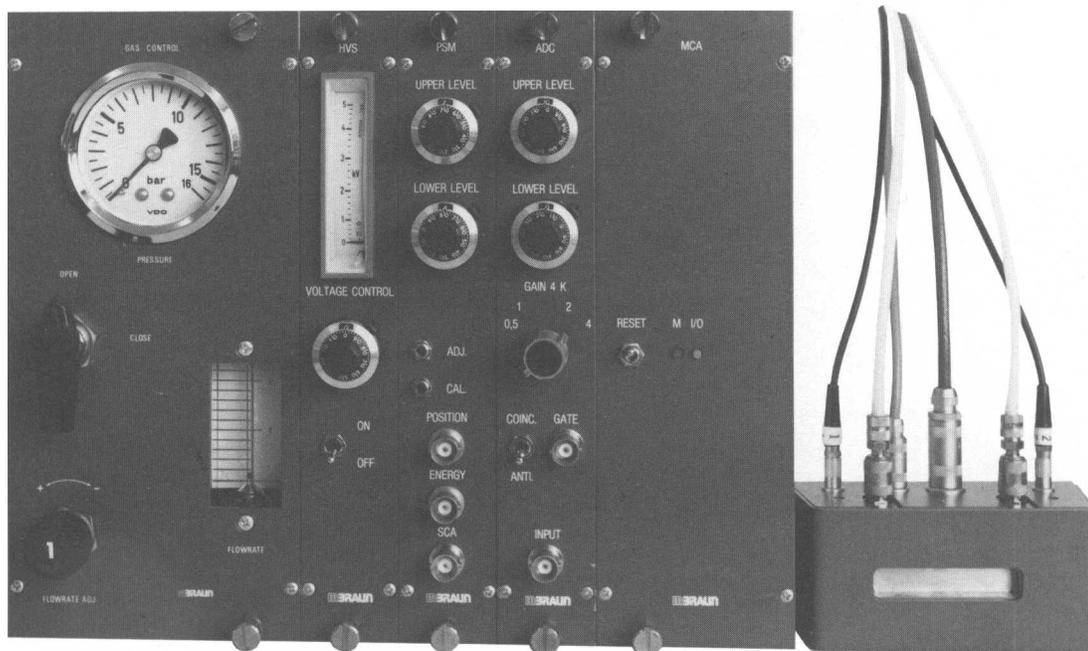


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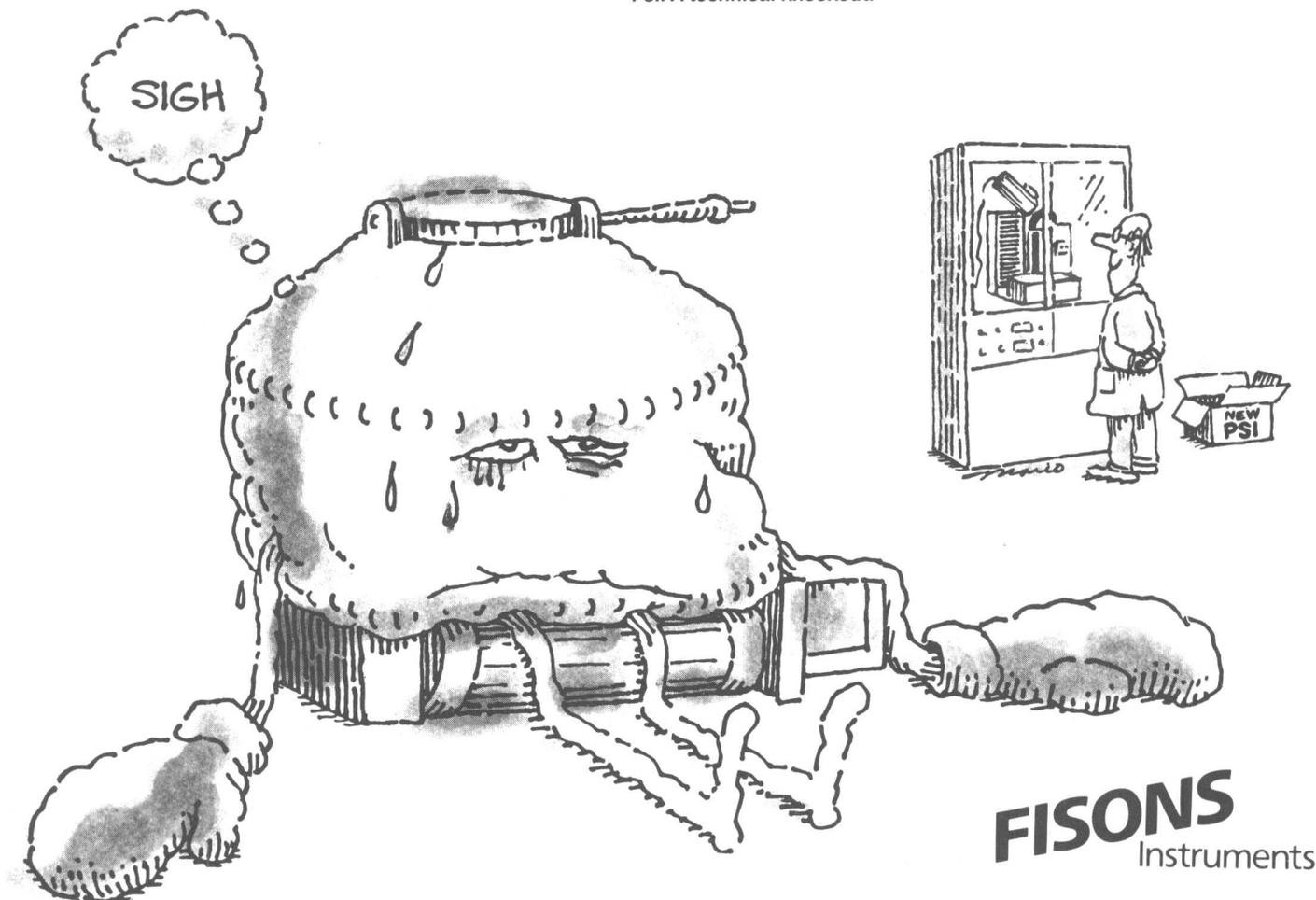
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* Max current	: 60 mA
* Stability	: +/-0.01%
* Filament volt.	: 0/13 volt
* Digital meters	: kV and mA
* Shutter controls	: remote
* Water safety flow switch	
* Weight	: 40 kg
* Dimensions W,H,D	: 48x22x60 cm

The TUBE SHIELD, designed with safety in mind, is provided with mechanical safety shutters and remotely controlled electromagnetically operated shutters. Red flashing lights warn the operator when the shutter is open, and opto-electronic devices prevent the opening of any shutters if no camera or diffractometer is placed in front of the tube-shield windows.

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Tube shield



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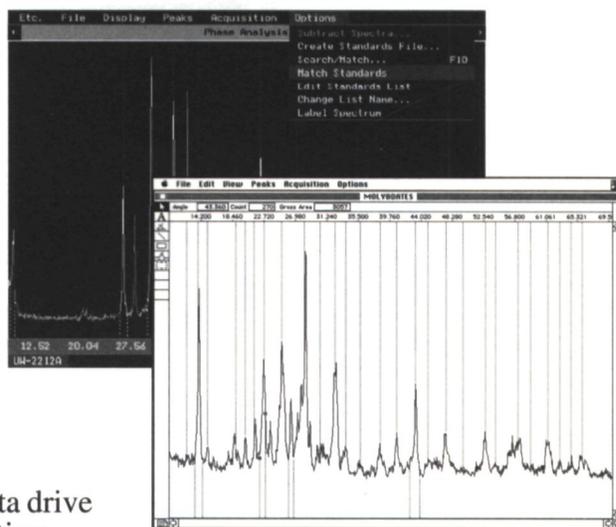
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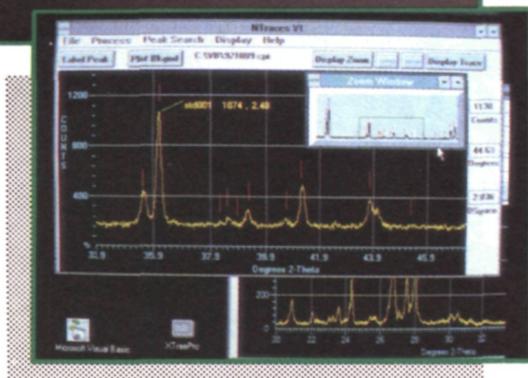
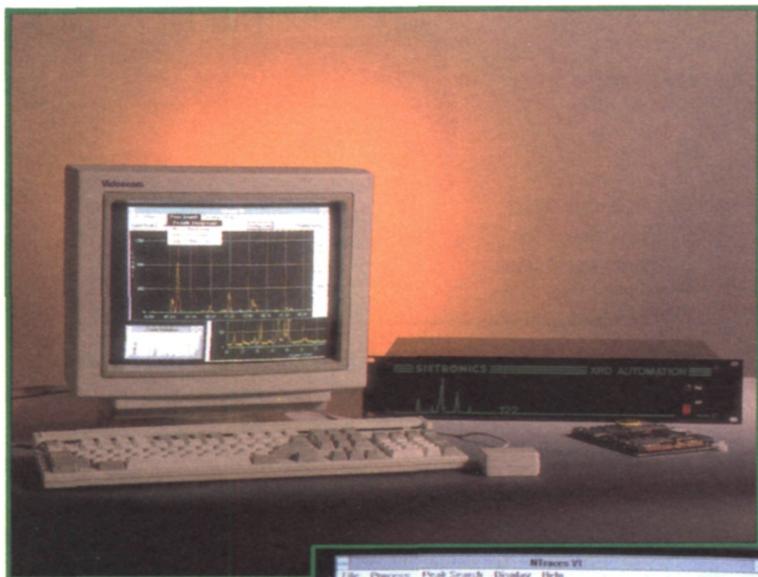


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PC-based automation for any x-ray diffractometer. $\theta/2\theta$ coupled or de-coupled modes, control for sample loaders, texture attachments, etc, available. Collects data independently of the controlling PC.

SIETRONICS SIE122D Software

The "live" scan display, simple menu and pushbutton operation makes data collection straightforward.

The all-new graphical processing package takes advantage of the multitasking power of Microsoft Windows to make scan data processing and publication quality output easier than ever before.

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Search-match with Fein Marquart's μ PDSM, use a spreadsheet or a word processor - all at the same time as you collect data.

SIETRONICS SIROQUANT Pattern Synthesis Quantification

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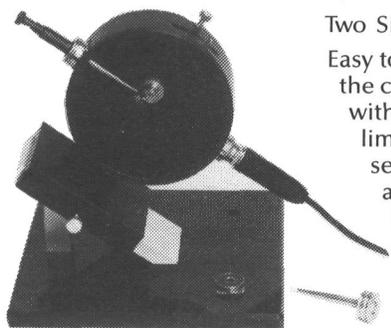
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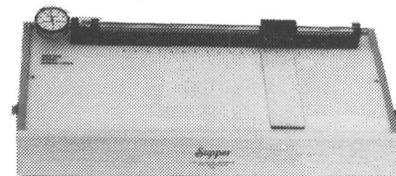
114.6mm Powder Camera with optional viewing stand, illuminator, and Gandolfi "Single Crystal Randomizer" which is interchangeable with standard powder sample holders

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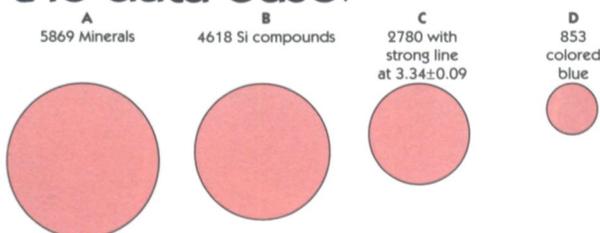
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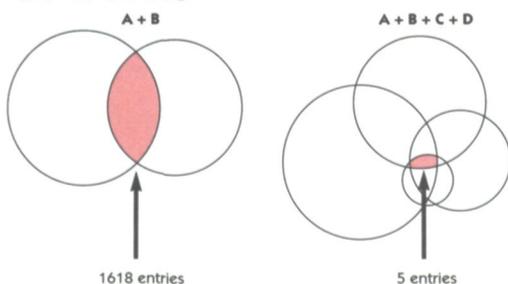
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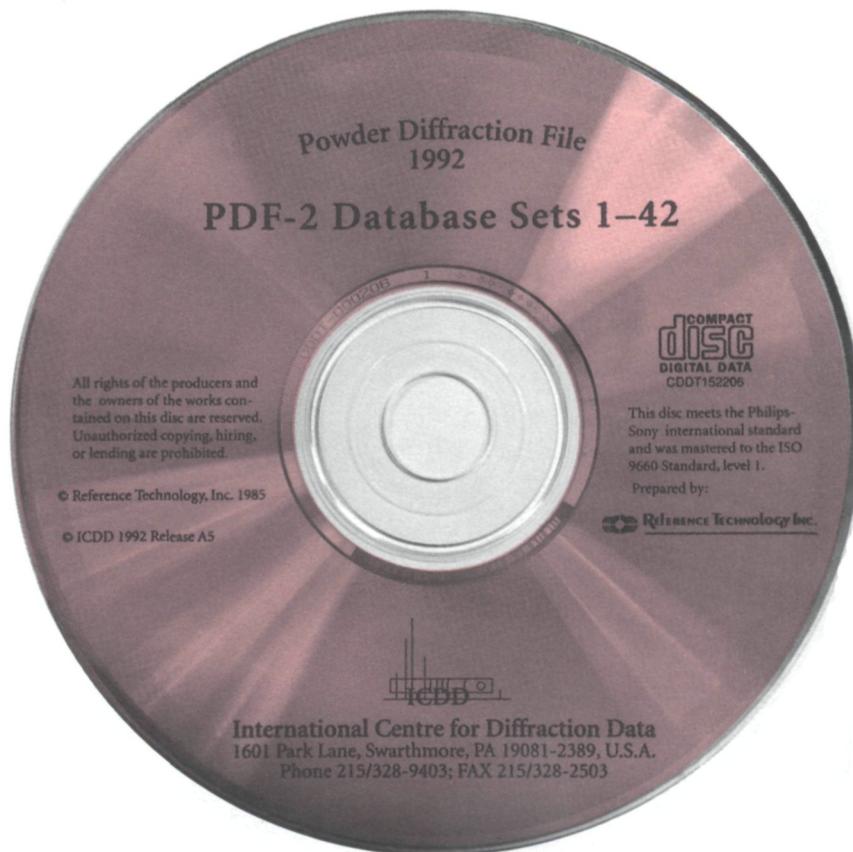
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Editorial

The American Institute of Physics to Produce *Powder Diffraction*

Beginning with the first issue of 1993, *Powder Diffraction* will be produced by the American Institute of Physics. AIP, for the International Centre for Diffraction Data. Ownership of *Powder Diffraction* and all copyrights will remain with ICDD.

This new arrangement will transfer many of the operations now performed by ICDD, and/or by contract, to the AIP publications group. ICDD will remain responsible for the basic editorial policies and for the selection of material to be published in each issue of the Journal. Included among the operations being transferred to AIP will be: editorial services, all aspects of production as well as advertising and circulation. Readers will be aware of very few changes in these areas except for certain matters of style, wherein ICDD will defer to AIP standards; page size will also change slightly. Stylistic changes in article presentation will be noted in the forthcoming Guide for Authors (to be distributed with the December issue of PD), but for those wishing greater detail, an AIP Style Manual is available. It may be obtained from the American Institute of Physics, c/o AIDC, 64 Depot Road, Colchester, VT 05466, U.S.A. for \$10 plus shipping charge (\$2.75 in the U.S. and \$7.50 for non-U.S.) prepaid. The publication may also be ordered with a credit card by calling 800-488-2665.

Processing manuscripts will not be affected in any way. As before, to expedite correspondence during the review stage, all manuscripts, including those with new data, should be sent to the geographically closest Editor. Once an Editor has accepted a manuscript it will be entered into the production schedule at AIP and, if the figures are acceptable, the text will be computer set as at present and the author will receive page proofs promptly. Authors, as they now are, will continue to be responsible for the ultimate accuracy of the manuscript. Again, as is now being done, assistance in clarification of English text will be provided and authors will have the opportunity to review changes in galley proof.

Subscriptions and advertising will be handled by appropriate offices within the AIP. Current subscribers will be notified directly for continuation of subscriptions. Advertising rates will not be affected by the change. Because the ownership of PD will still remain with ICDD, all rates will continue to be recommended by the Managing Editor.

Editors and Staff of PD welcome this new association. We look forward to a long and mutually beneficial relationship.

Deane K. Smith
Editor in Chief